

**Search Notes****Application/Control No.**

10/689,721

**Examiner**

ALEX LIEW

**Applicant(s)/Patent under  
Reexamination**

BAN ET AL.

**Art Unit**

2624

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
382/106,153,154 limited to text search	7/30/2008	AL